1. Record Nr.          UNISA996210260003316

   Titolo               Defect and Fault-Tolerance in VLSI Systems, 1995 Workshop

   Pubbl/distr/stampa   [Place of publication not identified], : IEEE Computer Society Press,
                        1995

   Descrizione fisica   1 online resource (320 pages)

   Disciplina           004.2

   Soggetti             Fault-tolerant computing

                        Integrated circuits - Very large scale integration - Design and
                        construction

   Lingua di pubblicazione   Inglese

   Formato              Materiale a stampa

   Livello bibliografico   Monografia

   Note generali        Bibliographic Level Mode of Issuance: Monograph

   Sommario/riassunto   An invited talk recounts Intel's experience with increasing die yield
                        through CAD algorithms, and a panel discussion examines tools for the
                        extracting of critical areas for a yield analysis of VLSI design. Others of
                        the 34 papers cover critical area analysis, defect sensitivity and
                        reliability, fault tolerant architectures and arrays, yield projection and
                        enhancement, fault tolerant and testing techniques, and self-checking
                        and coding techniques. No subject index. Annotation copyright by Book
                        News, Inc., Portland, OR.